Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/807,880	MCEWAN, WAYNE E.
Examiner	Art Unit
Huyen Le	3751

	SEARCHED					
Class	Subclass	Date	Examiner			
401	136-140	7/7/2006	HL			
	183					
	268					
	282					
	289					
	290					
	updated					
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
US-PGPUB		7/7/2006	HL		

SEARCH NOT (INCLUDING SEARCH	STRATEGY)
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